

NIST Smart Manufacturing Systems Test Bed

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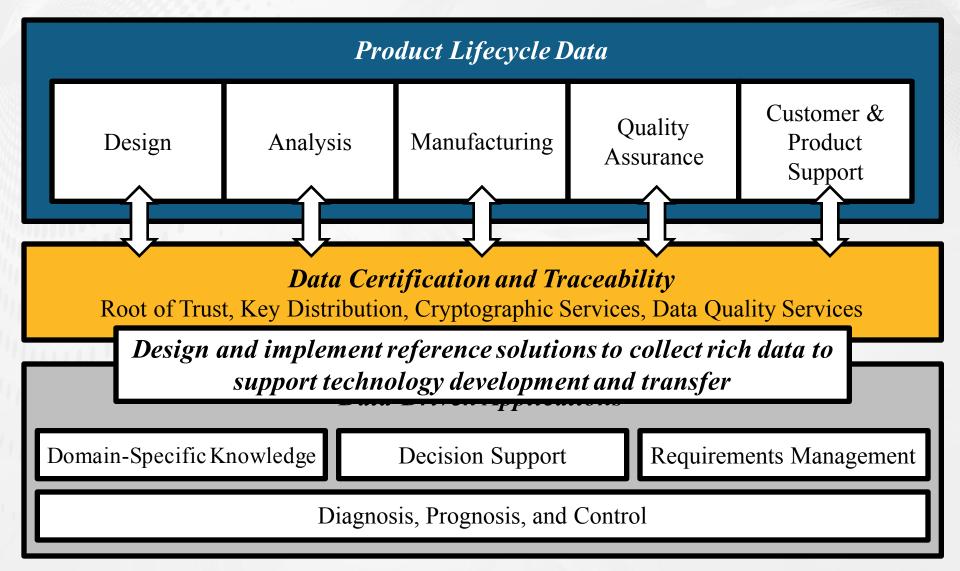


Disclaimer

 Identification of commercial systems does not imply recommendation or endorsement by NIST

 Identified commercial systems are not necessarily the best available for the purpose

Lifecycle Information Framework



Current Challenges

- PLM solutions:
 - CAx: CAD, CAE, CAM, etc.
 - PDM
 - V&V

Primarily IT; Engineering focused; Relatively expensive

- Operations solutions:
 - Devices, SCADA, PLC
 - MES, MOM
 - ERP

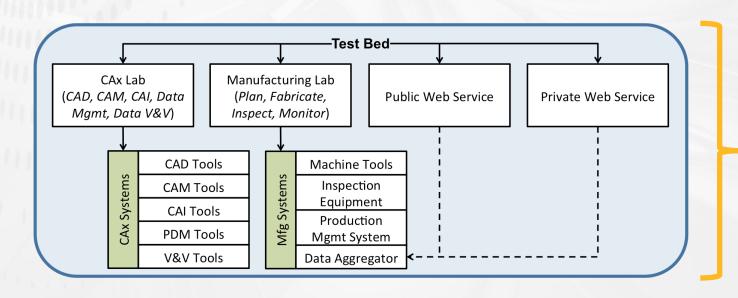
Mixture of IT and OT; Lack of integration across control levels

Integration of heterogeneous solutions across the product lifecycle for SMEs and larger organizations

NIST Smart Mfg. Systems Test Bed

Goals:

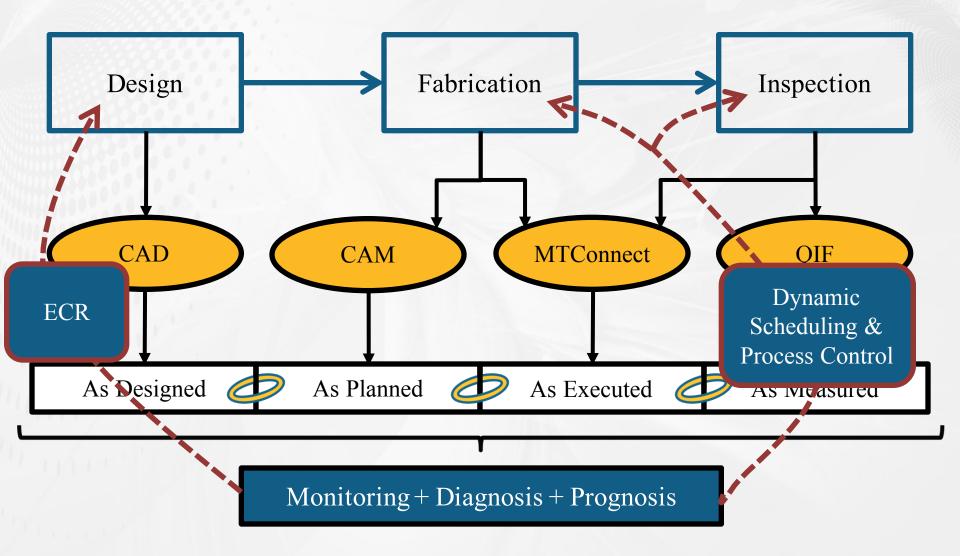
- Reference architecture and implementation
- Rich source of data for research community
- Physical infrastructure for standards and technology development
- Demonstration test cases
- Improvements in Fabrication Technology operations



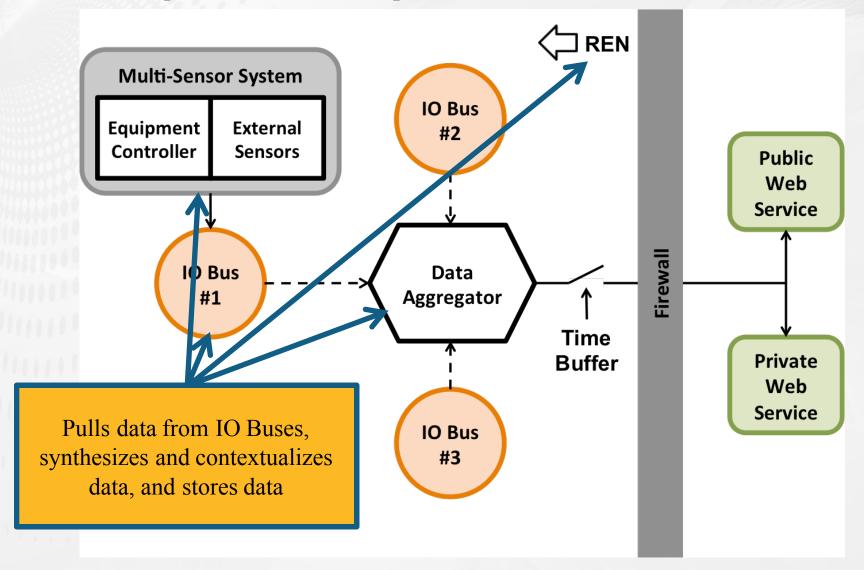
Prototype complete

Full deployment <u>May 1st</u>

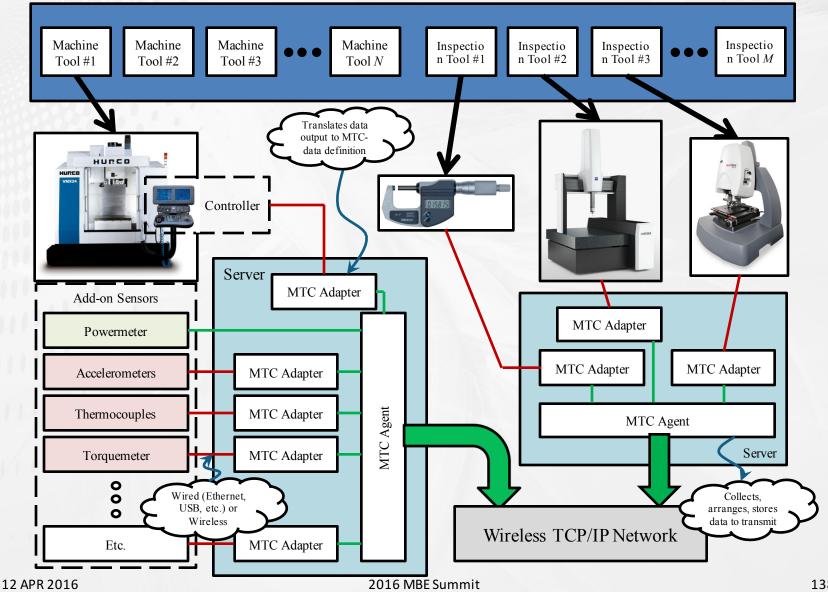
Data Collection and Aggregation



Shop-Floor Implementation



MTConnect: Key Mfg. Standard



Public and Private Web Services

- Public web service
 - Volatile data streams of manufacturing data from processes and equipment
 - Query-able database repository
 - Data packages for testing, verification, and validation
- Private web service
 - Similar to public web service except includes data and information shared internally that is not ready for public release

Volatile Data Stream



instanceId: 1459827175

version: 1.3.0.16

bufferSize: 131072

nextSequence: 214354

firstSequence: 83282

lastSequence: 214353

Target Launch Date: May 1st

Device: NIST-SMS-TestBed-5Axis; UUID: nist_testbed_GF_Agie_1_3a0e8a

Rotary: A

Samples

Timestamp	Туре	Sub Type	Name	Id	Sequence	Value
2016-04-05T14:11:29.684741	Anale	ACTUAL	Aposition	A 92	207523	-0.0001

Rotary : C Samples

Timestamp	Туре	Sub Type	Name	Id	Sequence	Value
2016-04-05T12:48:28.634491	Angle	ACTUAL	Cposition	C_90	181108	0.0278

Device: NIST-SMS-TestBed-5Axis

Events

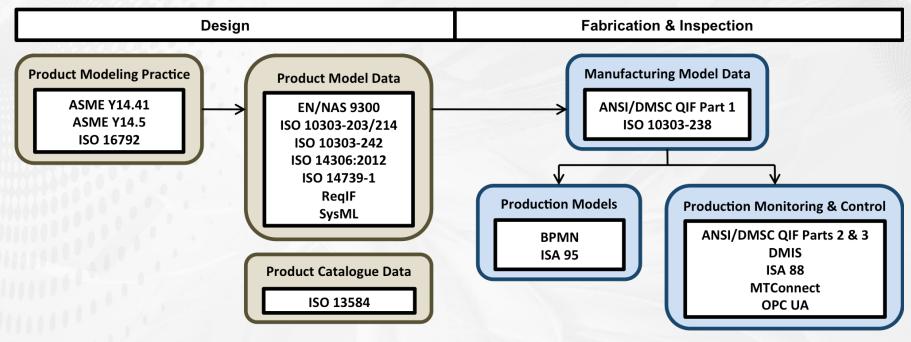
Timestamp	Туре	Sub Type	Name	Id	Sequence	Value
2016-04- 05T14:10:55.190783	AssetChanged			GF_Agie_1_78_asset_chg		.06_FEM- 3FLT
2016-04- 05T03:32:55.976037Z	AssetRemoved			GF_Agie_1_78_asset_rem	69	UNAVAILABLE
2016-04- 05T11:11:21.617246	Availability		avail	dtop_79	123411	AVAILABLE
2016-04- 05T11:11:21.617353	EmergencyStop		estop	dtop_80	123412	ARMED

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Virtual Factory Data

- Test bed can serve as virtual factory since data is presented for each process or equipment on shop floor
- Data does not need to be validated against a real system
- Data is presented in "raw" form including any deficiencies expected from industrial environments
- Data enables fabrication-focused research, including:
 - Data preprocessing, validation, robustness, and quality
 - Condition monitoring, diagnosis, and prognosis
 - Process monitoring and data analytics

Standards and Technology Development



Test and validate enhancements to standards

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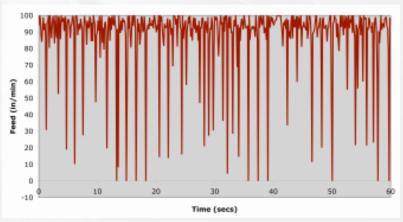
- Integrate domain standards to connect information across design and manufacturing
- Develop optimized data packages for technology verification and validation

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Demonstration: Feed Analysis

- Feed influences:
 - Quality of finished machined surface
 - Time required to complete operation
- Acceleration of feed drives causes discrepancy between actual and commanded feed

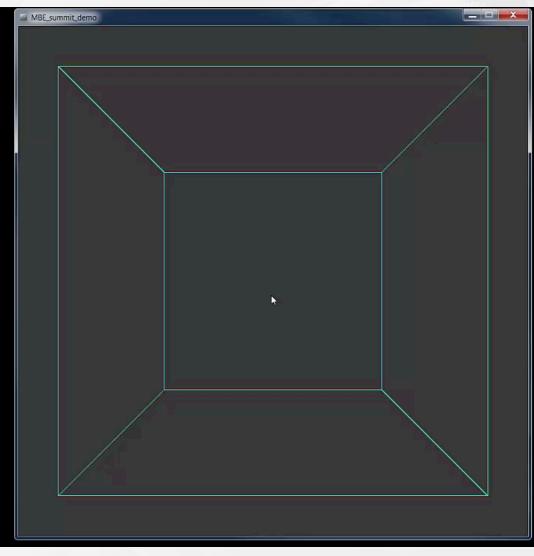
Important to identify where and when discrepancy occurs



Vijayaraghavan et al. (2008)



Demonstration: Feed Analysis



Applying Info to Improve Processes

- [**Design**] Can we redesign geometry to avoid the need for toolpaths with high feed discrepancies?
- [*Planning*] Can we redesign toolpath to minimize impact of machine dynamics?
- [Machining] Can we enable operator to make informed decisions?
- [Inspection] Can we use information to identify areas for more detailed measurement?

Summary

May 1st target for full deployment

 Reference implementation documents – guides, recommendations, specifications, methods – to be released

Please stay tuned for more info!

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